

Notice of References Cited	Application/Control No. 10/757,360		Applicant(s)/Patent Under Reexamination KRIZ ET AL.	
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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,482,710	11-2002	Oda et al.	438/311
*	B	US-5,986,326	11-1999	Kato, Hiroshi	257/593
*	C	US-6,211,029	04-2001	Kinoshita, Yasushi	438/357
*	D	US-2001/0003667	06-2001	AHN et al.	438/344
*	E	US-5,204,276	04-1993	Nakajima et al.	438/366
*	F	US-5,185,276	02-1993	Chen et al.	438/309
*	G	US-5,504,018	04-1996	Sato, Fumihiko	438/350
*	H	US-6,004,855	12-1999	Pollock et al.	438/342
*	I	US-5,994,196	11-1999	Seog, Jeon Hee	438/370
*	J	US-2001/0009793	07-2001	Sato, Fumihiko	438/342
*	K	US-6,455,364	09-2002	Asai et al.	438/235
*	L	US-6,440,810	08-2002	Johansson et al.	438/309
*	M	US-6,180,442	01-2001	Gris, Yvon	438/202

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	
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	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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